

*Please amend the abstract of the disclosure as follows:*

ABSTRACT

~~The invention relates to a~~ A method for correcting defects in X-ray images ~~in which includes identifying~~ potentially defective picture elements (p) ~~are identified~~ in X-ray images (I), ~~which are~~ created during normal operation, by comparing ~~the~~ a value (W(p)) of ~~said~~ the picture elements with corresponding values in a neighborhood (n(p)). If a picture element (p) has been classified as "potentially defective" in more than a specified percentage of X-ray images, it is entered in a defect map which is refreshed on a continuous basis. The defect map can then be used to correct other X-ray images.